

## SCOPE :

This specification applies to the Pb Free high current type SMD inductors for  
MSCD-53-SERIES

## PRODUCT IDENTIFICATION

**MSCD- 53 - 100 K-RU**

①    ②    ③    ④

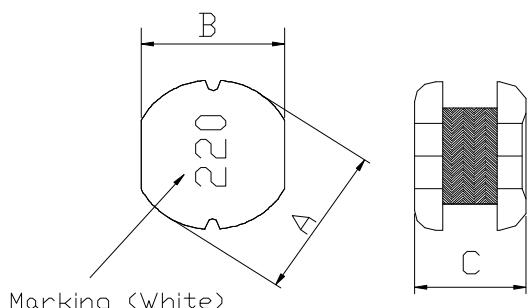
① Product Code

② Dimensions Code

③ Inductance Code

④ Tolerance Code

## (1) SHAPES AND DIMENSIONS



A:	$5.8 \pm 0.3$	mm
B:	$5.2 \pm 0.3$	mm
C:	$3.0 \pm 0.3$	mm
D:	2.0 Typ.	mm

## (2) ELECTRICAL SPECIFICATIONS

SEE TABLE 1

### TEST INSTRUMENTS

L : HP 4284A PRECISION LCR METER (or equivalent)

RDC : CHROMA MODEL 16502 MILLIOHMMETER (or equivalent)

## (3) CHARACTERISTICS

(3)-1 Ambient temperature ..... +60°C Max.

(3)-2 Operate temperature range ..... -40°C ~ +125°C  
(Including self temp. rise)

(3)-3 Storage temperature range ..... -40°C ~ +125°C



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**TABLE 1**

MAGLAYERS PT/NO.	Inductance L(μH)	Percent Tolerance	Test Frequency	Resistance RDC(Ω)Max.	Rated DC Current IDC(A)	Marking
MSCD-53-1R0□-RU	1.0	M,N	100kHz/0.25V	30m	4.50	1R0
MSCD-53-1R4□-RU	1.4	M,N	100kHz/0.25V	30m	4.10	1R4
MSCD-53-1R5□-RU	1.5	M,N	100kHz/0.25V	30m	4.00	1R5
MSCD-53-1R8□-RU	1.8	M,N	100kHz/0.25V	30m	3.70	1R8
MSCD-53-2R2□-RU	2.2	M,N	100kHz/0.25V	30m	3.50	2R2
MSCD-53-2R7□-RU	2.7	M,N	100kHz/0.25V	40m	3.20	2R7
MSCD-53-3R3□-RU	3.3	M,N	100kHz/0.25V	50m	2.80	3R3
MSCD-53-3R9□-RU	3.9	M,N	100kHz/0.25V	60m	2.60	3R9
MSCD-53-4R7□-RU	4.7	M,N	100kHz/0.25V	70m	2.50	4R7
MSCD-53-5R6□-RU	5.6	M,N	100kHz/0.25V	80m	2.40	5R6
MSCD-53-6R8□-RU	6.8	M,N	100kHz/0.25V	90m	2.20	6R8
MSCD-53-8R2□-RU	8.2	M,N	100kHz/0.25V	0.10	2.00	8R2
MSCD-53-100□-RU	10	K,L,M	100kHz/0.25V	0.12	1.80	100
MSCD-53-120□-RU	12	L,M	100kHz/0.25V	0.13	1.75	120
MSCD-53-150□-RU	15	L,M	100kHz/0.25V	0.15	1.70	150
MSCD-53-180□-RU	18	L,M	100kHz/0.25V	0.18	1.60	180
MSCD-53-220□-RU	22	L,M	100kHz/0.25V	0.22	1.30	220
MSCD-53-270□-RU	27	K,L,M	100kHz/0.25V	0.26	1.20	270
MSCD-53-330□-RU	33	K,L,M	100kHz/0.25V	0.33	1.10	330
MSCD-53-390□-RU	39	L,M	100kHz/0.25V	0.42	1.00	390
MSCD-53-470□-RU	47	K,L,M	100kHz/0.25V	0.50	0.90	470
MSCD-53-560□-RU	56	L,M	100kHz/0.25V	0.55	0.85	560
MSCD-53-680□-RU	68	L,M	100kHz/0.25V	0.65	0.80	680
MSCD-53-820□-RU	82	L,M	100kHz/0.25V	0.80	0.65	820
MSCD-53-101□-RU	100	K,M	100kHz/0.25V	0.90	0.60	101
MSCD-53-121□-RU	120	K,M	100kHz/0.25V	1.00	0.58	121
MSCD-53-151□-RU	150	K,M	100kHz/0.25V	1.30	0.43	151
MSCD-53-181□-RU	180	K,M	100kHz/0.25V	1.50	0.41	181
MSCD-53-221□-RU	220	K,M	100kHz/0.25V	2.00	0.38	221
MSCD-53-271□-RU	270	K,M	100kHz/0.25V	2.50	0.35	271
MSCD-53-331□-RU	330	K,M	100kHz/0.25V	3.20	0.28	331
MSCD-53-391□-RU	390	K,M	100kHz/0.25V	3.50	0.26	391
MSCD-53-471□-RU	470	K,M	100kHz/0.25V	4.20	0.20	471
MSCD-53-561□-RU	560	K,M	100kHz/0.25V	4.50	0.19	561
MSCD-53-681□-RU	680	K,M	100kHz/0.25V	6.50	0.18	681
MSCD-53-821□-RU	820	K,M	100kHz/0.25V	7.50	0.15	821
MSCD-53-102□-RU	1000	K,M	100kHz/0.25V	8.00	0.13	102

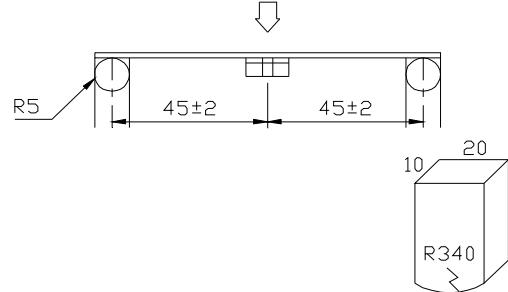
※ □ specify the inductance tolerance,K(±10%),L(±15%),M(±20%),N(±30%)

※ IDC : Based on inductance change ( $\Delta L/L_0$  : drop 10% Max.) @ ambient temp. 25°C and  
Based on temperature rise ( $\Delta T$  : 40°C TYP.)

M A G . L A Y E R S

## (4) RELIABILITY TEST METHOD

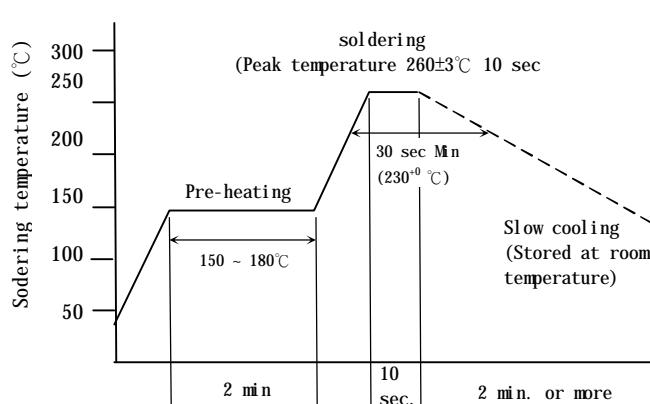
### MECHANICAL

TEST ITEM	SPECIFICATION	TEST DETAILS
Substrate bending	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage or electrical damage.	<p>The sample shall be soldered onto the printed circuit board in figure 1 and a load applied until the figure in the arrow direction is made approximately 3mm.(keep time 30 seconds)</p> <p>PCB dimension shall the page 7/9</p> <p style="text-align: center;">F(Pressurization)</p>  <p style="text-align: center;">PRESSURE ROD figure-1</p>
Vibration	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	<p>The sample shall be soldered onto the printed circuit board and when a vibration having an amplitude of 1.52mm and a frequency of from 10 to 55Hz/1 minute repeated should be applied to the 3 directions (X,Y,Z) for 2 hours each.</p> <p>(A total of 6 hours)</p>
Solderability	New solder More than 90%	<p>Flux (rosin, isopropyl alcohol{JIS-K-1522}) shall be coated over the whole of the sample before hard, the sample shall then be preheated for about 2 minutes in a temperature of 130~150°C and after it has been immersed to a depth 0.5mm below for 3±0.2 seconds fully in molten solder M705 with a temperature of 245±5°C.</p> <p>More than 90% of the electrode sections shall be covered with new solder smoothly when the sample is taken out of the solder bath.</p>



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## MECHANICAL

TEST ITEM	SPECIFICATION	
Resistance to Soldering heat (reflow soldering)	<p>There shall be no damage or problems.</p>  <p>The graph shows Soldering temperature (°C) on the y-axis (50 to 300) and time on the x-axis. The pre-heating phase rises from 50°C to 150°C (~180°C) over 2 minutes. The soldering phase peaks at 260±3°C for 10 seconds, with a minimum of 230°C for 30 seconds. The slow cooling phase follows, stored at room temperature for 2 minutes or more.</p>	<p><b>Temperature profile of reflow soldering</b></p> <p>The specimen shall be passed through the reflow oven with the condition shown in the above profile for 1 time.</p> <p>The specimen shall be stored at standard atmospheric conditions for 1 hour, after which the measurement shall be made.</p>

## ELECTRICAL

TEST ITEM	SPECIFICATION	TEST DETAILS
Insulation resistance	<p>There shall be no other damage or problems.</p>	<p>DC 100V voltage shall be applied across this sample of top surface and the terminal.</p> <p>The insulation resistance shall be more than <math>1 \times 10^8 \Omega</math>.</p>
Dielectric withstand voltage	<p>There shall be no other damage or problems.</p>	<p>AC 100V voltage shall be applied for 1 minute across the top surface and the terminal of this sample</p>
Temperature characteristics	<p><math>\Delta L/L20^\circ\text{C} \leq \pm 10\%</math></p> <p>0~2000 ppm/°C</p>	<p>The test shall be performed after the sample has stabilized in an ambient temperature of -20 to +85°C, and the value calculated based on the value applicable in a normal temperature and normal humidity shall be <math>\Delta L/L20^\circ\text{C} \leq \pm 10\%</math>.</p>



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## ENVIRONMENT CHARACTERISTICS

TEST ITEM	SPECIFICATION																
High temperature storage	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	The sample shall be left for $96 \pm 4$ hours in an atmosphere with a temperature of $85 \pm 2^\circ\text{C}$ and a normal humidity. Upon completion of the measurement shall be made after the sample has been left in a normal temperature and normal humidity for 1 hour.															
Low temperature	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	The sample shall be left for $96 \pm 4$ hours in an atmosphere with a temperature of $-25 \pm 3^\circ\text{C}$ . Upon completion of the test, the measurement shall be made after the sample has been left in a normal temperature and normal humidity for 1 hour.															
Change of temperature	$\Delta L/L_0 \leq \pm 5\%$ There shall be no other damage or problems	The sample shall be subject to 5 continuous cycles, such as shown in the table 2 below and then it shall be subjected to standard atmospheric conditions for 1 hour, after which measurement shall be made.															
		<b>table 2</b> <table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th></th> <th>Temperature</th> <th>Duration</th> </tr> </thead> <tbody> <tr> <td>1</td> <td><math>-25 \pm 3^\circ\text{C}</math> (Thermostat No.1)</td> <td>30 min.</td> </tr> <tr> <td>2</td> <td>Standard atmospheric</td> <td>No.1 → No.2</td> </tr> <tr> <td>3</td> <td><math>85 \pm 2^\circ\text{C}</math> (Thermostat No.2)</td> <td>30 min.</td> </tr> <tr> <td>4</td> <td>Standard atmospheric</td> <td>No.2 → No.1</td> </tr> </tbody> </table>		Temperature	Duration	1	$-25 \pm 3^\circ\text{C}$ (Thermostat No.1)	30 min.	2	Standard atmospheric	No.1 → No.2	3	$85 \pm 2^\circ\text{C}$ (Thermostat No.2)	30 min.	4	Standard atmospheric	No.2 → No.1
	Temperature	Duration															
1	$-25 \pm 3^\circ\text{C}$ (Thermostat No.1)	30 min.															
2	Standard atmospheric	No.1 → No.2															
3	$85 \pm 2^\circ\text{C}$ (Thermostat No.2)	30 min.															
4	Standard atmospheric	No.2 → No.1															
Moisture storage	$\Delta L/L_0 \leq \pm 5\%$ There shall be no mechanical damage.	The sample shall be left for $96 \pm 4$ hours in a temperature of $40 \pm 2^\circ\text{C}$ and a humidity(RH) of $90 \sim 95\%$ . Upon completion of the test, the measurement shall be made after the sample has been left in a normal temperature and normal humidity more than 1 hour.															
<b>Test conditions :</b> The sample shall be reflow soldered onto the printed circuit board in every test.																	



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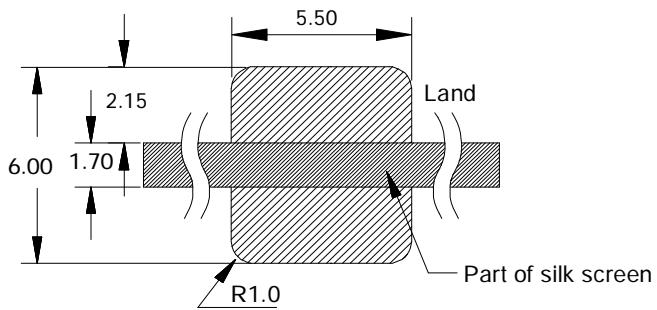
## (5) LAND DIMENSION (Ref.)

PCB: GLASS EPOXY  $t=1.6\text{mm}$

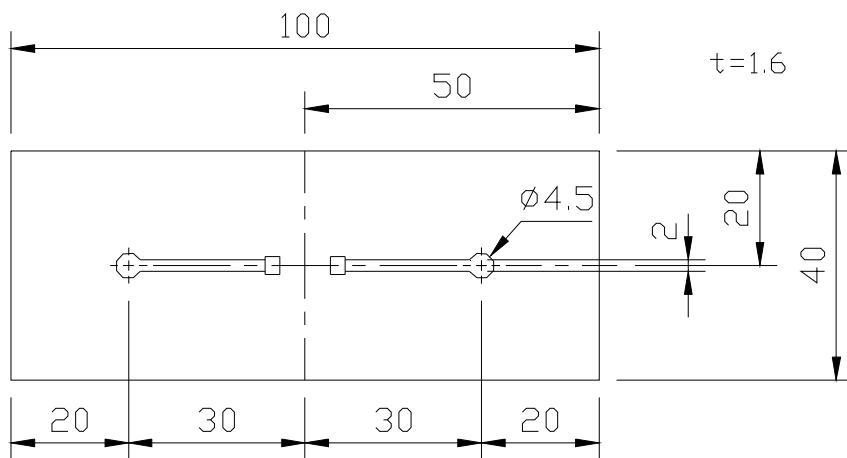
### (5)-1 LAND PATTERN DIMENSIONS

(STANDARD PATTERN)

Unit:mm



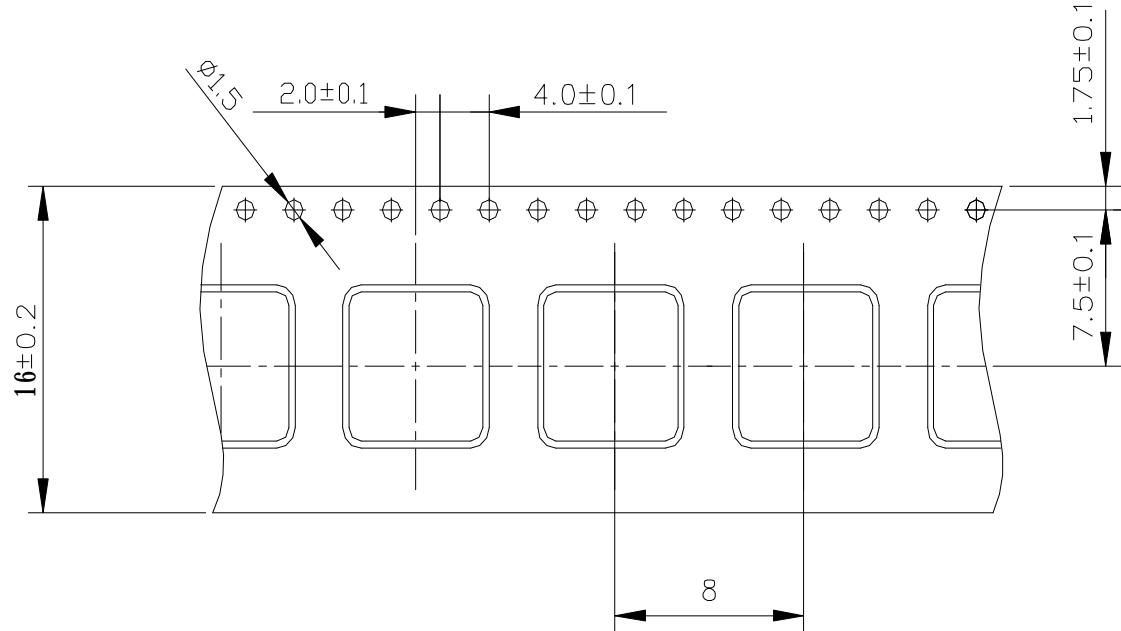
### (5)-2 SUBSTRATE BENDING TEST BENDING TEST BOARD



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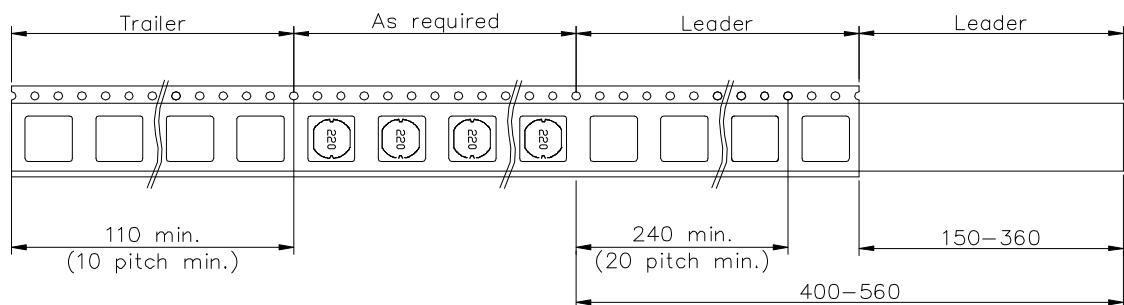
## (6) PACKAGING

### (6)-1 CARRIER TAPE DIMENSIONS (mm)



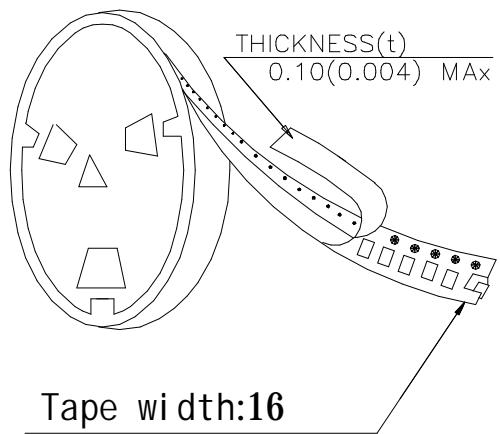
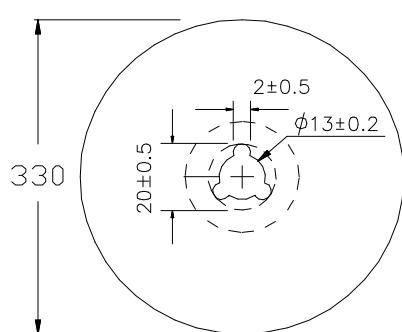
### (6)-2 TAPING DIMENSIONS (mm)

Unreeling  
Direction



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## (6)-3 REEL DIMENSIONS (mm)



## (6)-4 QUANTITY

2000pcs/Reel

The products are packaged so that no damage will be sustained.



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